



# 81CXXX/81NXXX

**CMOS IC**

## VOLTAGE DETECTORS WITH BUILT-IN DELAY TIME

### DESCRIPTION

The UTC **81CXXX** and **81NXXX** series are good performance voltage detector and manufactured by CMOS technologies with highly accurate, low power consumption. A delay circuit is built-in to each detector, therefore, peripherals are unnecessary and high density mounting is possible. Detect voltage is extremely accurate with minimal temperature drift. Both CMOS and N-channel open drain output configurations are available.

### FEATURES

- \*Highly Accurate : Detect voltage  $\pm 2\%$
- \*Built-In Delay time : 1ms ~ 50ms,  
50ms ~ 200ms,  
200ms ~ 400ms,
- \*Detect Voltage Temperature Characteristics:  
TYP  $\pm 100$ ppm/
- \*Wide Operating Voltage Range : 0.7V ~ 10.0V
- \*Low Current Consumption : TYP 1.0  $\mu$ A ( $V_{IN}=2.0V$ )

### ORDERING INFORMATION

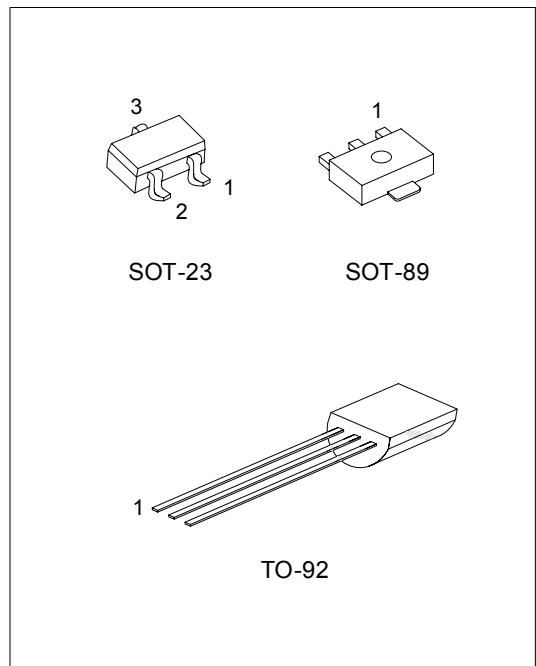
CMOS:

Order Number		:Delay Time		Package	Pin Assign.			Packing		
Normal	Lead Free Plating	Duration	Code		1	2	3			
81Cxx- -AB3-E-R	81CxxL- -AB3-E-R	1 ~ 50 ms	P	SOT-89	O	I	G	Tape Reel		
81Cxx- -AE3-3-R	81CxxL- -AE3-3-R			SOT-23	O	G	I	Tape Reel		
81Cxx- -AE3-5-R	81CxxL- -AE3-5-R			SOT-23	G	O	I	Tape Reel		
81Cxx- -T92-D-B	81CxxL- -T92-D-B			50 ~ 200 ms	Q	TO-92	I	G	O	Tape Box
81Cxx- -T92-E-B	81CxxL- -T92-E-B			200 ~ 400 ms	R	TO-92	O	I	G	Tape Box
81Cxx- -T92-D-K	81CxxL- -T92-D-K					TO-92	I	G	O	Bulk
81Cxx- -T92-E-K	81CxxL- -T92-E-K					TO-92	O	I	G	Bulk
						TO-92	O	I	G	Bulk

N-Channel:

Order Number		:Delay Time		Package	Pin Assign.			Packing		
Normal	Lead Free Plating	Duration	Code		1	2	3			
81Nxx- -AB3-E-R	81NxxL- -AB3-E-R	1 ~ 50 ms	H	SOT-89	O	I	G	Tape Reel		
81Nxx- -AE3-3-R	81NxxL- -AE3-3-R			SOT-23	O	G	I	Tape Reel		
81Nxx- -AE3-5-R	81NxxL- -AE3-5-R			SOT-23	G	O	I	Tape Reel		
81Nxx- -T92-D-B	81NxxL- -T92-D-B			50 ~ 200 ms	J	TO-92	I	G	O	Tape Box
81Nxx- -T92-E-B	81NxxL- -T92-E-B			200 ~ 400 ms	K	TO-92	O	I	G	Tape Box
81Nxx- -T92-D-K	81NxxL- -T92-D-K					TO-92	I	G	O	Bulk
81Nxx- -T92-E-K	81NxxL- -T92-E-K					TO-92	O	I	G	Bulk
						TO-92	O	I	G	Bulk

Note: 1. Pin assignment: I:Vin O:Vout G:Vss  
2.xx: Output Voltage, refer to Marking Information.



\*Pb-free plating product number: 81CXXXL/81NXXXL

### ORDERING INFORMATION(Cont.)

<p>81CxxL-①-AB3-x-R</p>	<p>(1)Packing Type (2)Pin Code (3)Package Type (4)Delay Time (5)Lead Plating (6)Output Voltage Code (7)Output Configuration</p>	<p>(1) R: Tape Reel, B: Tape Box, K: Bulk (2) refer to Pin Assignment (3) AB3: SOT-89, AE3: SOT-23, T92: TO-92 (4) ①: refer to Delay Time (5)L: Lead Free Plating, Blank: Pb/Sn (6) xx: refer to Marking Information (7) C: CMOS, N: N-Cannel</p>
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### MARKING INFORMATION

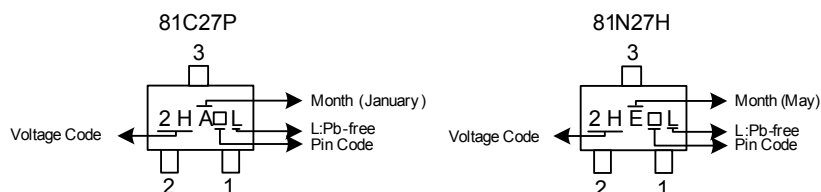
PACKAGE	VOLTAGE CODE			MARKING		
SOT-89	10:1.0V					
	11:1.1V	26:2.6V				
	12:1.2V	27:2.7V	40:4.0V			
	13:1.3V	28:2.8V	41:4.1V			
	14:1.4V	29:2.9V	42:4.2V			
	15:1.5V	30:3.0V	43:4.3V			
	16:1.6V	31:3.1V	44:4.4V			
	17:1.7V	32:3.2V	45:4.5V			
	18:1.8V	33:3.3V	46:4.6V			
	19:1.9V	34:3.4V	47:4.7V			
	20:2.0V	35:3.5V	48:4.8V			
	21:2.1V	36:3.6V	49:4.9V			
	22:2.2V	37:3.7V	50:5.0V			
	23:2.3V	38:3.8V				
	24:2.4V	39:3.9V				
	25:2.5V					
	TO-92					

PACKAGE	INTEGER*	CODE	DECIMAL**	CODE	MARKING
SOT-23	1.	1	.0	A	
	2.	2	.1	B	
	3.	3	.2	C	
	4.	4	.3	D	
	5.	5	.4	E	
	6.	6	.5	F	
			.6	G	
			.7	H	
			.8	J	
			.9	K	

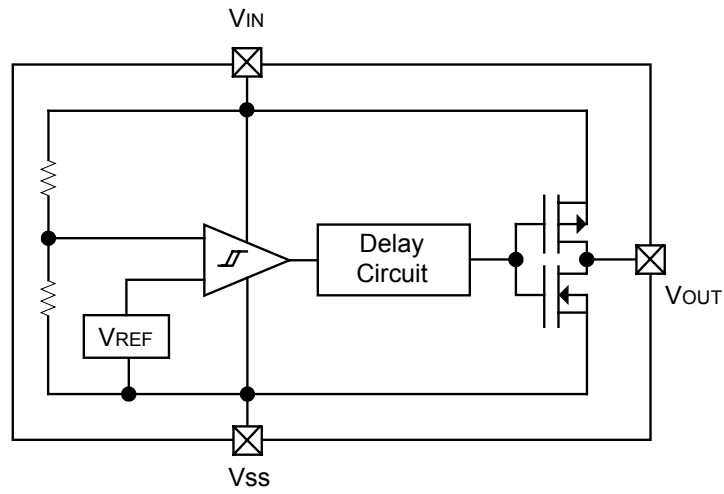
\* Represents the integer of the Detect Voltage

\*\* Represents the decimal number of the Detect Voltage

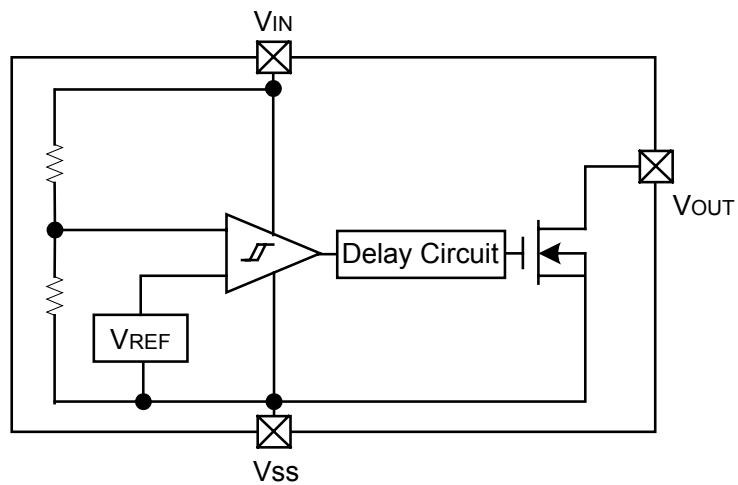
### EXAMPLE:



■ BLOCK DIAGRAM



CMOS Output



N-channel Open Drain Output

■ ABSOLUTE MAXIMUM RATINGS (Ta=25 )

PARAMETER		SYMBOL	RATINGS	UNIT
Input Voltage		V <sub>IN</sub>	12	V
Output Current		I <sub>OUT</sub>	50	mA
Output Voltage	CMOS	V <sub>OUT</sub>	V <sub>SS</sub> -0.3 ~ V <sub>IN</sub> +0.3	V
	N-Ch open drain		V <sub>SS</sub> -0.3 ~ 9	
Power Dissipation	SOT-23	P <sub>D</sub>	150	mW
	SOT-89		500	
	TO-92		300	
Operating Temperature		T <sub>OPR</sub>	-30 ~ +80	
Storage Temperature		T <sub>STG</sub>	-40 ~ +125	

Note Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Thermal Resistance Junction-Case	SOT-23	J <sub>C</sub>	200	/W
	SOT-89		100	
	TO-92		45	

■ ELECTRICAL CHARACTERISTICS (Ta=25 )

Detection voltage (1.0V ~ 1.9V)

PARAMETER	SYMBOL	CIRCUIT	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Detect Voltage	V <sub>DF</sub>	1		V <sub>DF</sub> (T) X0.98	V <sub>DF</sub> (T)	V <sub>DF</sub> (T) X1.02	V
Hysteresis Range	V <sub>HYS</sub>	1		V <sub>DF</sub> X0.02	V <sub>DF</sub> X0.05	V <sub>DF</sub> X0.08	V
Operating Voltage	V <sub>IN</sub>	1	V <sub>DF</sub> =1.6V ~ 6.0V	0.7		10.0	V
Supply Current	I <sub>SS</sub>	2	V <sub>IN</sub> =1.5V		0.9	2.6	μA
			V <sub>IN</sub> =5.0		2.0	4.2	μA
Output Current	I <sub>OUT</sub>	3	N-ch V <sub>DS</sub> =0.5V, V <sub>IN</sub> =1.0V		2.2		mA
		4	P-ch V <sub>DS</sub> =2.1V, V <sub>IN</sub> =8.0V (CMOS output)		-15.4		mA
V <sub>DF</sub> Temperature Characteristics	$\frac{\Delta V_{DF}}{\Delta T_{OPR} \times V_{DF}}$				±100		ppm/
Transient Delay Time (V <sub>DR</sub> → V <sub>OUT</sub> inversion)	t <sub>DLY</sub> *	5	V <sub>IN</sub> changes from 0.6V ~ 10V	50		200	ms

■ ELECTRICAL CHARACTERISTICS(Cont.)

Detection voltage (2.0V ~ 2.9V)

PARAMETER	SYMBOL	CIRCUIT	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Detect Voltage	$V_{DF}$	1		$V_{DF}(T)$ X0.98	$V_{DF}(T)$	$V_{DF}(T)$ X1.02	V
Hysteresis Range	$V_{HYS}$	1		$V_{DF}$ X0.02	$V_{DF}$ X0.05	$V_{DF}$ X0.08	V
Operating Voltage	$V_{IN}$	1	$V_{DF}=1.6V \sim 6.0V$	0.7		10.0	V
Supply Current	$I_{SS}$	2	$V_{IN}=2.0V$		1.0	3.0	$\mu A$
			$V_{IN}=5.0V$		2.0	4.2	$\mu A$
Output Current	$I_{OUT}$	3	N-ch $V_{DS}=0.5V, V_{IN}=2.0V$		7.9		mA
		4	P-ch $V_{DS}=2.1V, V_{IN}=8.0V$ (CMOS output)		-15.4		mA
$V_{DF}$ Temperature Characteristics	$\frac{\Delta V_{DF}}{\Delta T_{OPR} \times V_{DF}}$				$\pm 100$		ppm/
Transient Delay Time ( $V_{DR} \rightarrow V_{OUT}$ inversion)	$t_{DLY}^*$	5	$V_{IN}$ changes from 0.6V ~ 10V	50		200	ms

Detection voltage (3.0V ~ 3.9V)

PARAMETER	SYMBOL	CIRCUIT	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Detect Voltage	$V_{DF}$	1		$V_{DF}(T)$ X0.98	$V_{DF}(T)$	$V_{DF}(T)$ X1.02	V
Hysteresis Range	$V_{HYS}$	1		$V_{DF}$ X0.02	$V_{DF}$ X0.05	$V_{DF}$ X0.08	V
Operating Voltage	$V_{IN}$	1	$V_{DF}=1.6V \sim 6.0V$	0.7		10.0	V
Supply Current	$I_{SS}$	2	$V_{IN}=3.0V$		1.3	3.4	$\mu A$
			$V_{IN}=5.0V$		2.0	4.2	$\mu A$
Output Current	$I_{OUT}$	3	N-ch $V_{DS}=0.5V, V_{IN}=3.0V$		10.1		mA
		4	P-ch $V_{DS}=2.1V, V_{IN}=8.0V$ (CMOS output)		-15.4		mA
$V_{DF}$ Temperature Characteristics	$\frac{\Delta V_{DF}}{\Delta T_{OPR} \times V_{DF}}$				$\pm 100$		ppm/
Transient Delay Time ( $V_{DR} \rightarrow V_{OUT}$ inversion)	$t_{DLY}^*$	5	$V_{IN}$ changes from 0.6V ~ 10V	50		200	ms

■ ELECTRICAL CHARACTERISTICS(Cont.)

Detection voltage (4.0V ~ 4.9V)

PARAMETER	SYMBOL	CIRCUIT	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Detect Voltage	$V_{DF}$	1		$V_{DF}(T)$ X0.98	$V_{DF}(T)$	$V_{DF}(T)$ X1.02	V
Hysteresis Range	$V_{HYS}$	1		$V_{DF}$ X0.02	$V_{DF}$ X0.05	$V_{DF}$ X0.08	V
Operating Voltage	$V_{IN}$	1	$V_{DF}=1.6V \sim 6.0V$	0.7		10.0	V
Supply Current	$I_{SS}$	2	$V_{IN}=4.0V$		1.5	3.8	$\mu A$
			$V_{IN}=5.0V$		2.0	4.2	$\mu A$
Output Current	$I_{OUT}$	3	N-ch $V_{DS}=0.5V, V_{IN}=4.0V$		11.5		mA
		4	P-ch $V_{DS}=2.1V, V_{IN}=8.0V$ (CMOS output)		-15.4		mA
$V_{DF}$ Temperature Characteristics	$\frac{\Delta V_{DF}}{\Delta T_{OPR} \times V_{DF}}$				$\pm 100$		ppm/
Transient Delay Time ( $V_{DR} \rightarrow V_{OUT}$ inversion)	$t_{DLY}^*$	5	$V_{IN}$ changes from 0.6V ~ 10V	50		200	ms

Detection voltage (5.0V)

PARAMETER	SYMBOL	CIRCUIT	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Detect Voltage	$V_{DF}$	1		$V_{DF}(T)$ X0.98	$V_{DF}(T)$	$V_{DF}(T)$ X1.02	V
Hysteresis Range	$V_{HYS}$	1		$V_{DF}$ X0.02	$V_{DF}$ X0.05	$V_{DF}$ X0.08	V
Operating Voltage	$V_{IN}$	1	$V_{DF}=1.6V \sim 6.0V$	0.7		10.0	V
Supply Current	$I_{SS}$	2	$V_{IN}=5.0V$		2.0	4.2	$\mu A$
Output Current	$I_{OUT}$	3	N-ch $V_{DS}=0.5V, V_{IN}=5.0V$		13.0		mA
		4	P-ch $V_{DS}=2.1V, V_{IN}=8.0V$ (CMOS output)		-15.4		mA
$V_{DF}$ Temperature Characteristics	$\frac{\Delta V_{DF}}{\Delta T_{OPR} \times V_{DF}}$				$\pm 100$		ppm/
Transient Delay Time ( $V_{DR} \rightarrow V_{OUT}$ inversion)	$t_{DLY}^*$	5	$V_{IN}$ changes from 0.6V ~ 10V	50		200	ms

$V_{DF}(T)$ : established detect voltage value

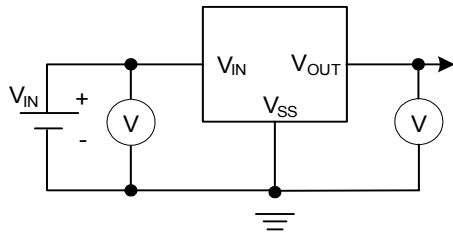
Release Voltage:  $V_{DR} = V_{DF} + V_{HYS}$

\* Transient Delay Time: 1ms ~ 50ms & 200ms ~ 400ms versions are also available.

Note: The power consumption during power-start to output being stable (release operation) is 2  $\mu A$  greater than it is after that period (completion of release operation) because of delay circuit through current.

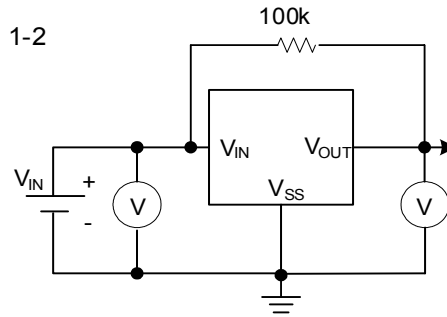
## TEST CIRCUITS

1-1



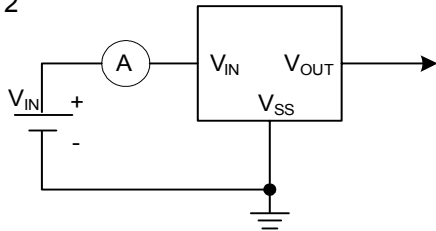
Cmos Output

1-2

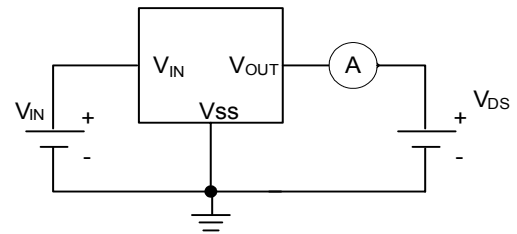


N-channel Open Drain Output

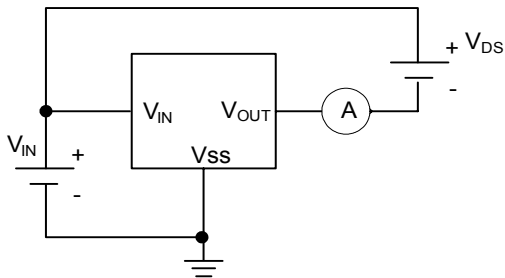
2



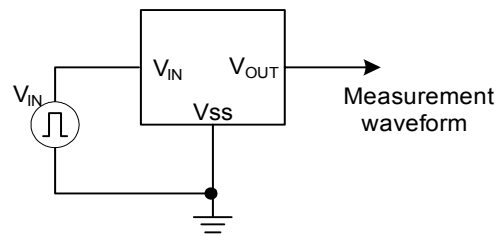
3



4

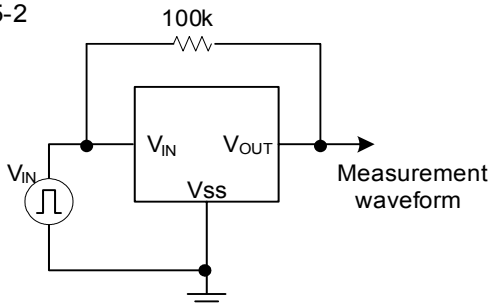


5-1



Cmos Output

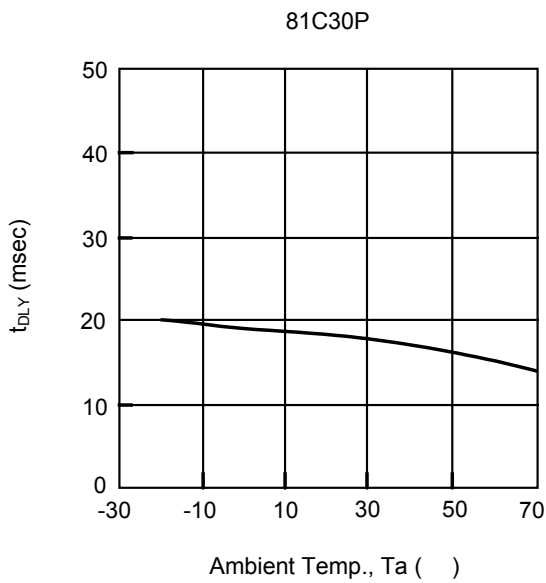
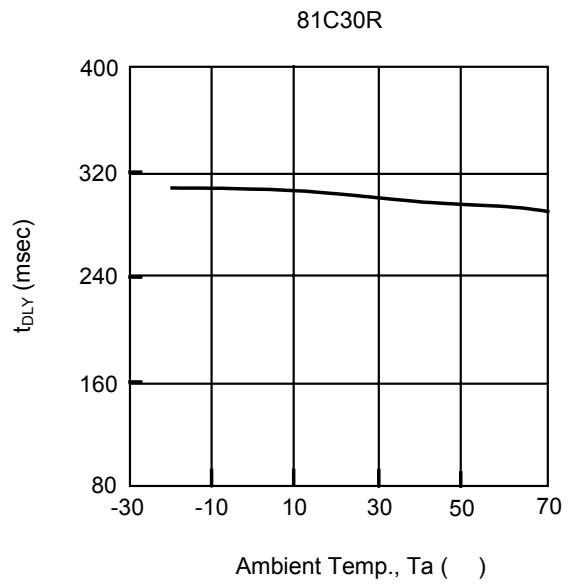
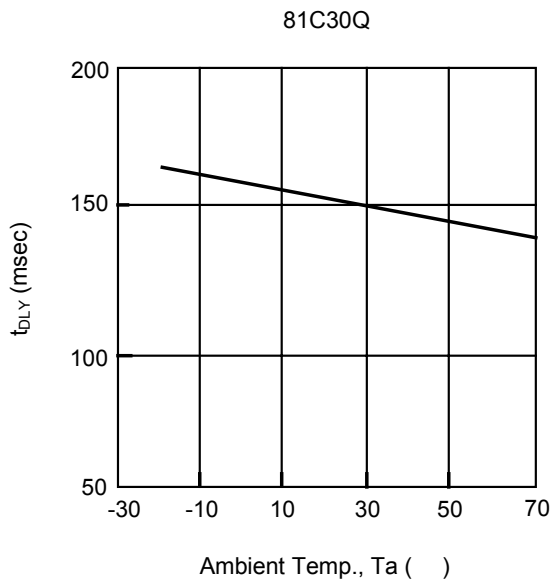
5-2



N-channel Open Drain Output

■ TYPICAL PERFORMANCE CHARACTERISTICS

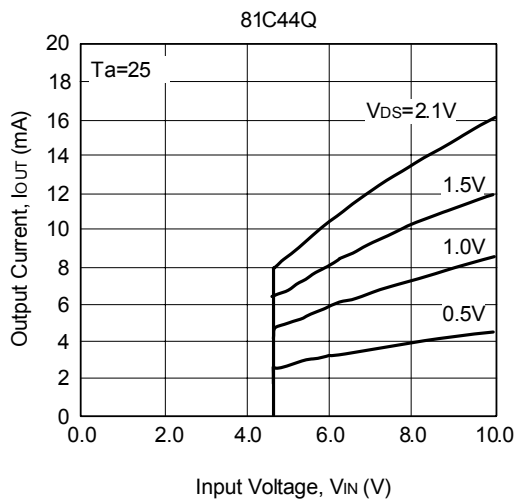
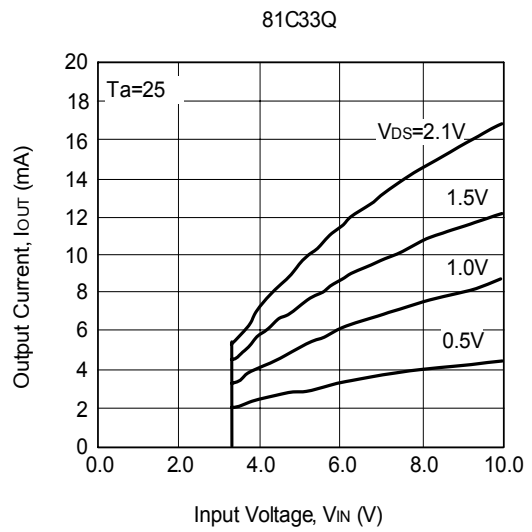
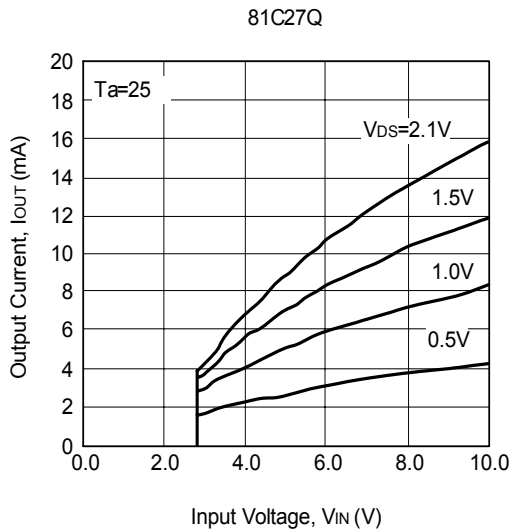
(1) AMBIENT TEMPERATURE vs. TRANSIENT DELAY TIME



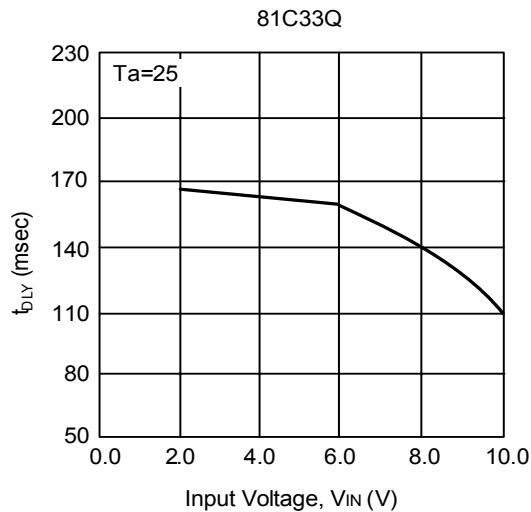


■ TYPICAL PERFORMANCE CHARACTERISTICS(Cont.)

(2) P-CHANNEL DRIVER OUTPUT CURRENT vs. INPUT VOLTAGE

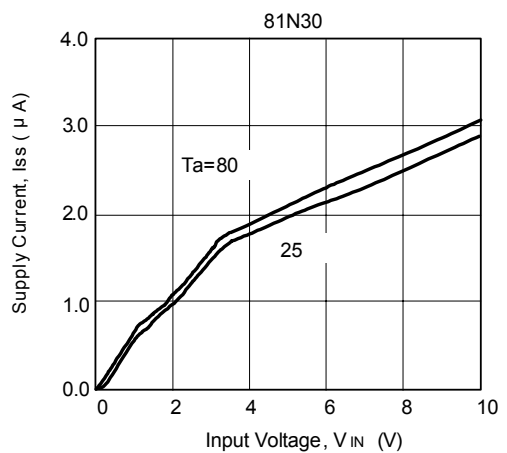
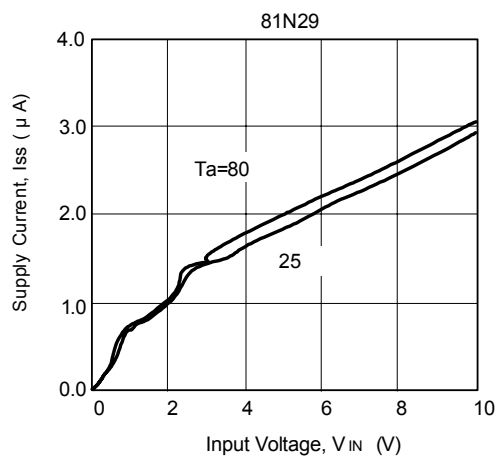
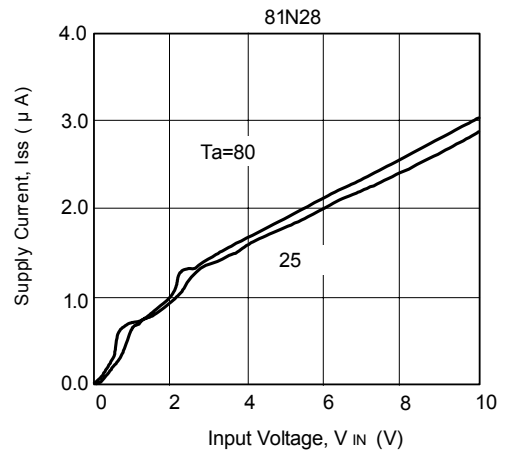
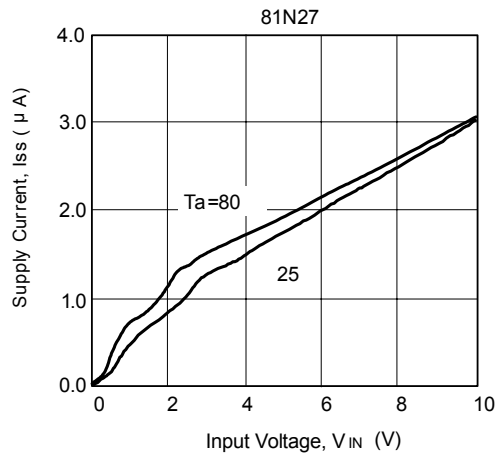
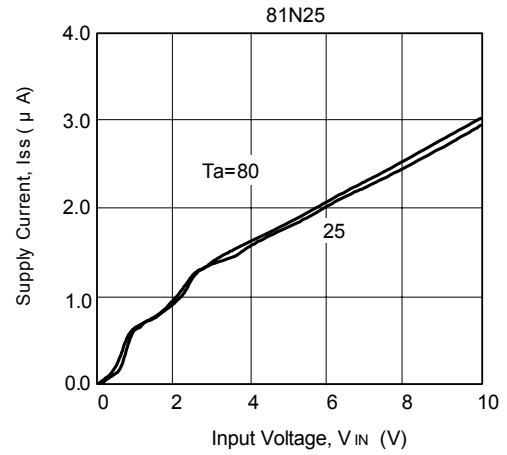
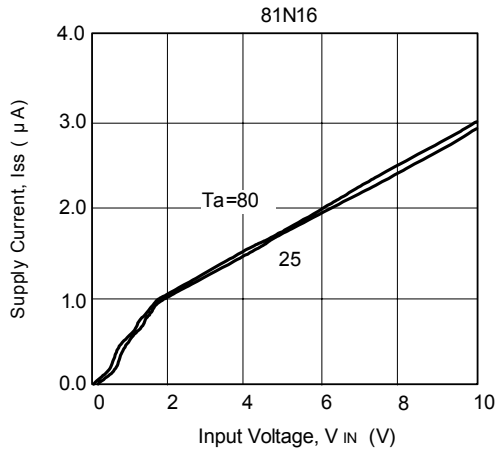


(2) TRANSIENT DELAY TIME vs. INPUT VOLTAGE

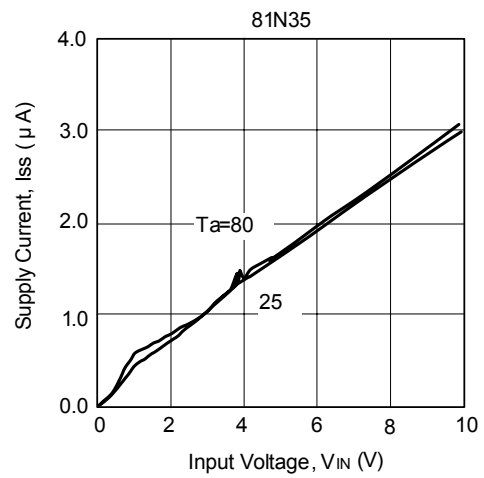
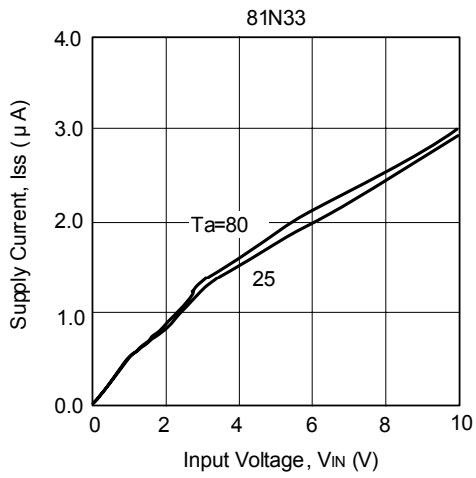


■ TYPICAL PERFORMANCE CHARACTERISTICS(Cont.)

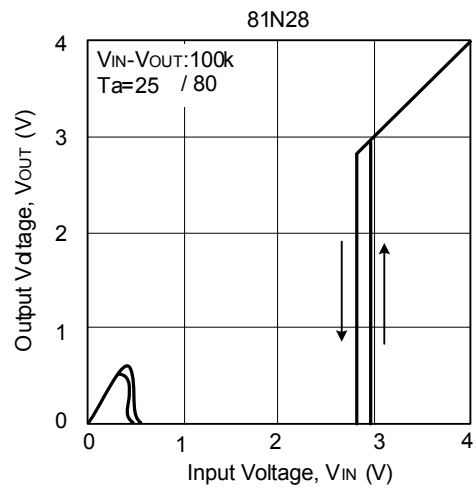
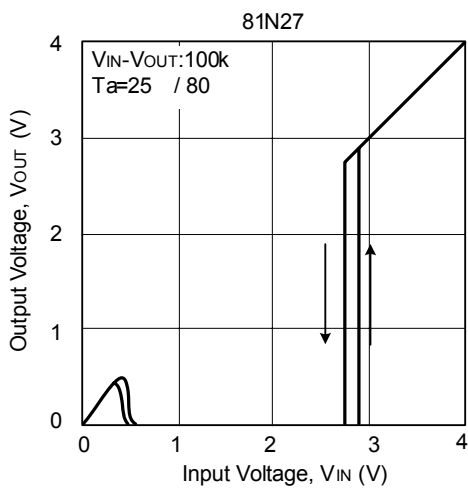
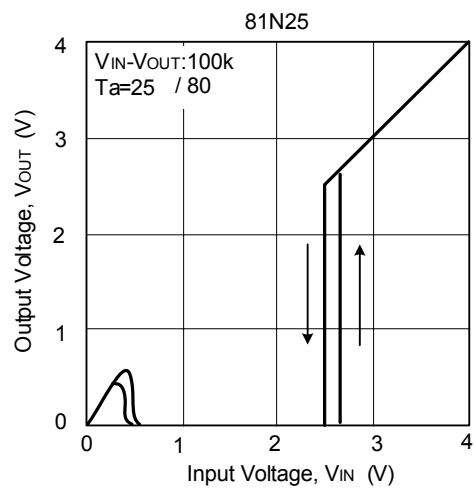
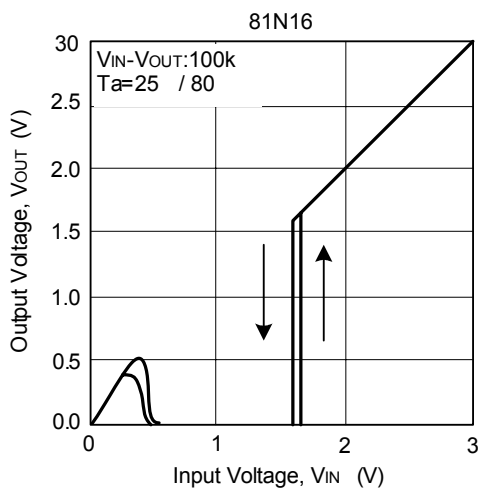
(3) SUPPLY CURRENT vs. INPUT VOLTAGE



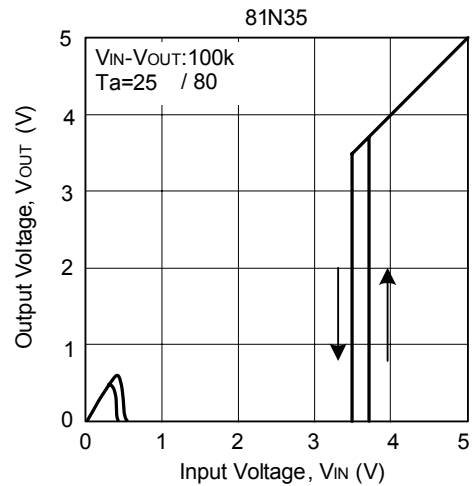
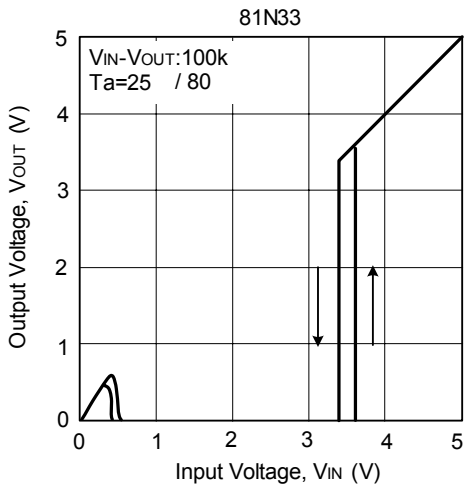
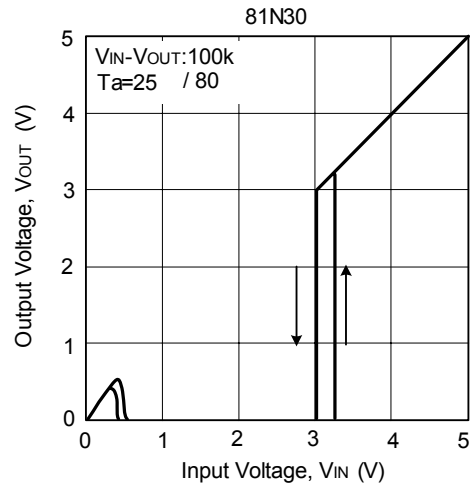
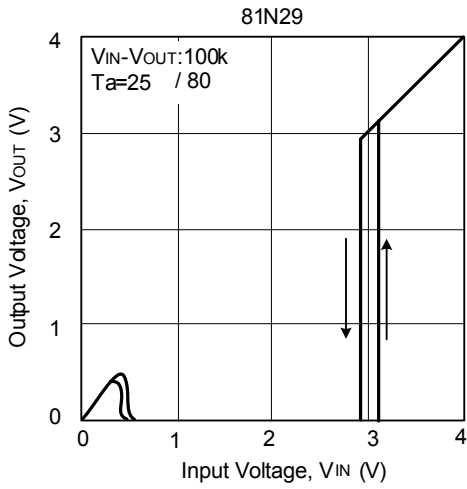
■ TYPICAL PERFORMANCE CHARACTERISTICS(Cont.)



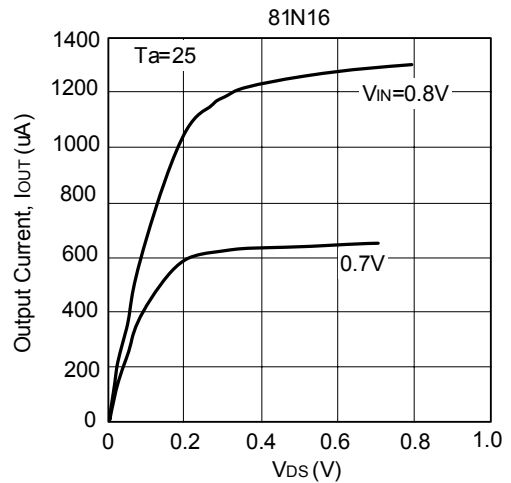
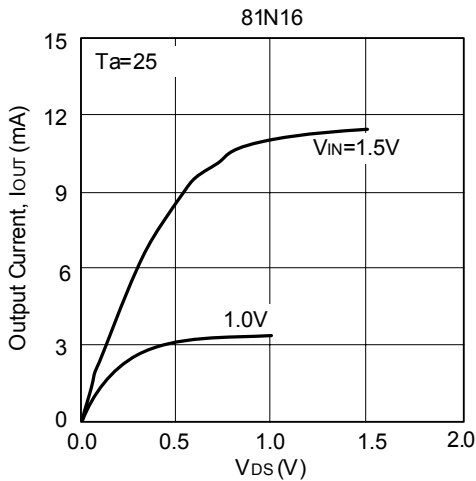
(4) OUTPUT VOLTAGE vs. INPUT VOLTAGE



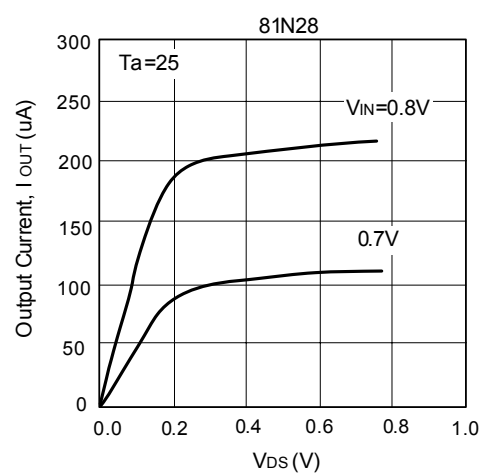
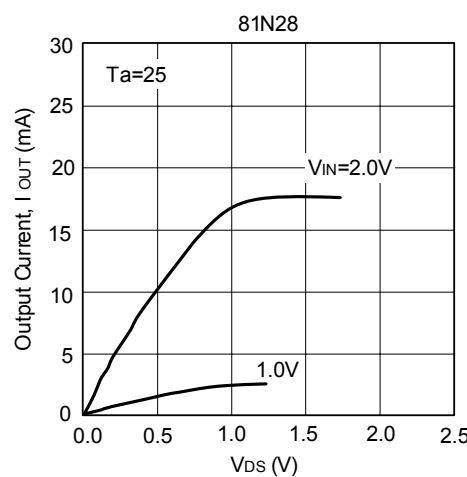
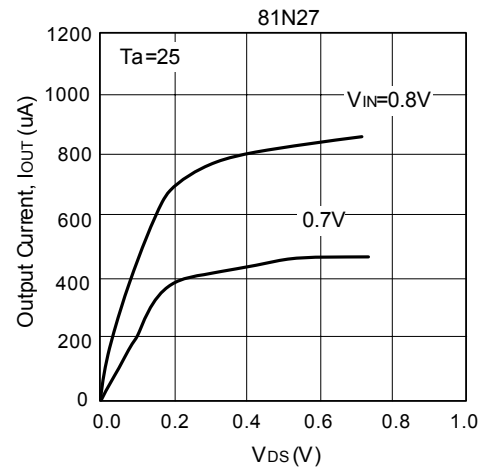
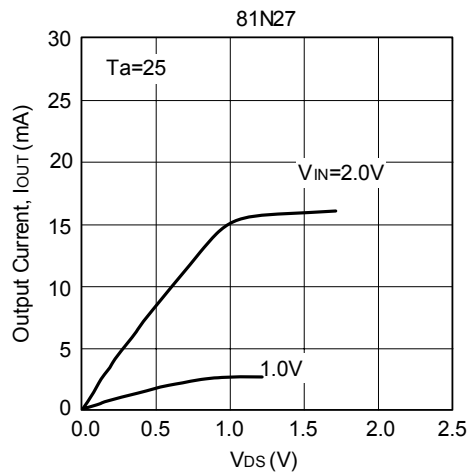
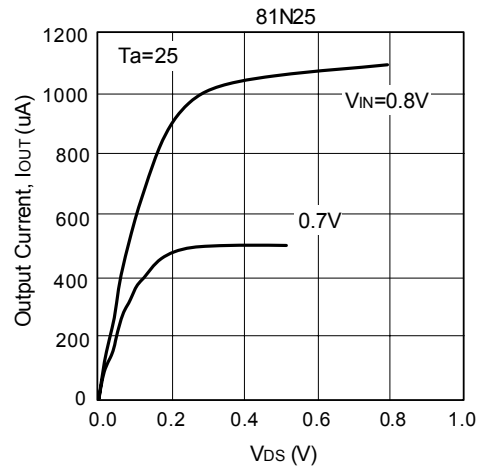
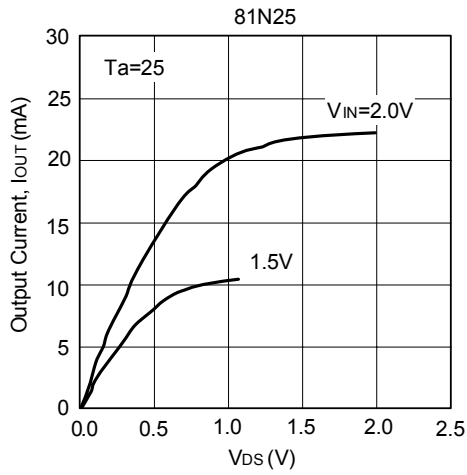
■ TYPICAL PERFORMANCE CHARACTERISTICS(Cont.)



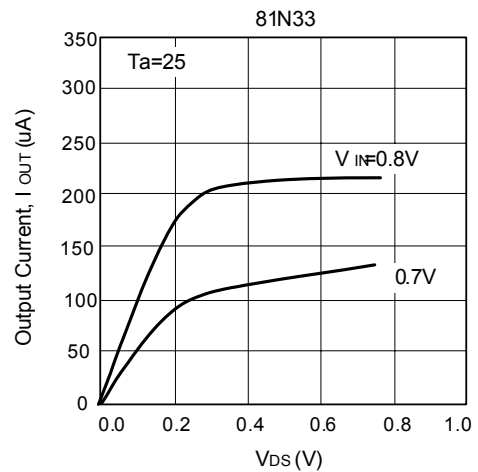
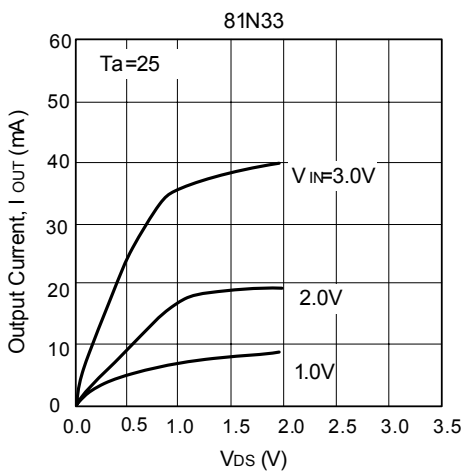
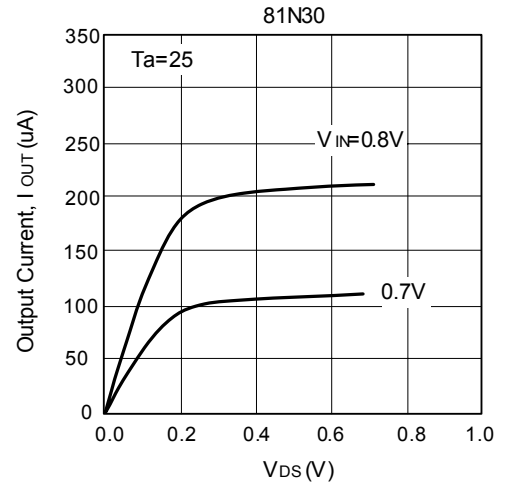
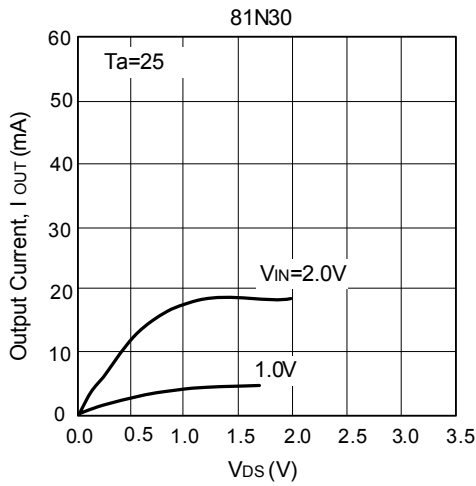
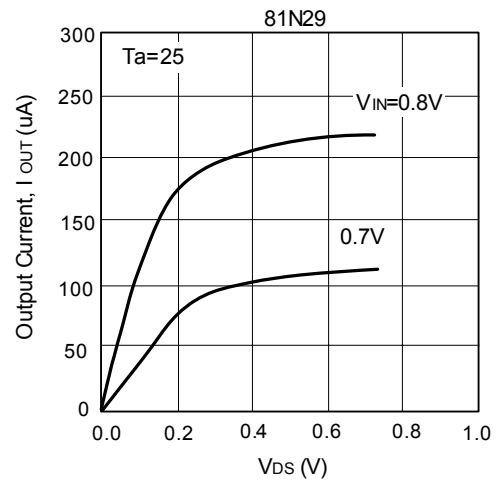
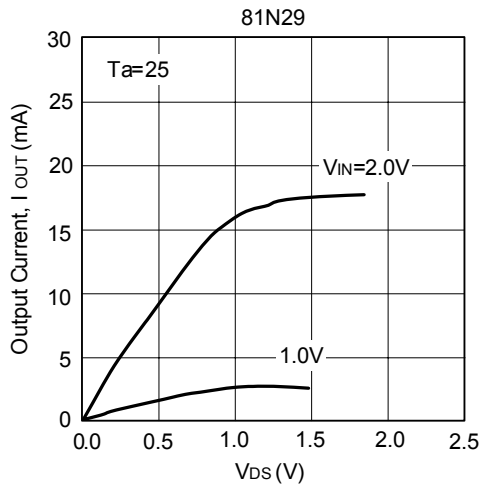
(5) N-CHANNEL DRIVRE OUTPUT CURRENT vs.  $V_{DS}$



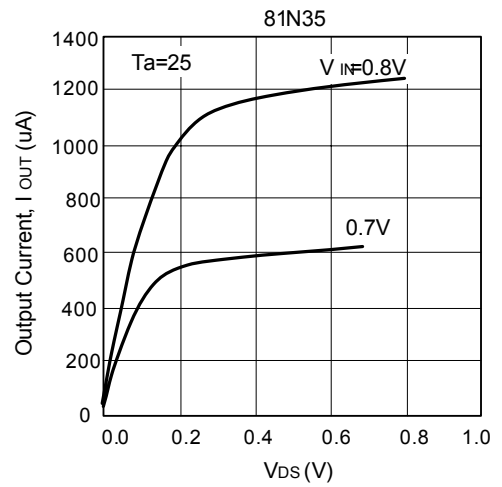
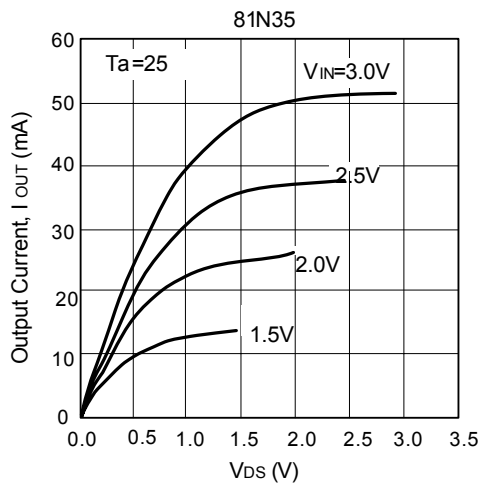
■ TYPICAL PERFORMANCE CHARACTERISTICS(Cont.)



■ TYPICAL PERFORMANCE CHARACTERISTICS(Cont.)



■ TYPICAL PERFORMANCE CHARACTERISTICS(Cont.)



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